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## Connector, Short Point Receptacle Contact

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### 1. SCOPE

#### 1.1. Content

This specification covers performance, tests and quality requirements for TE Connectivity (TE) short point receptacle contact and connector system. This contact is a separable electrical connection device for mating to .025 inch square posts. It can be crimped to 20 to 32 AWG wire sizes and is intended to be used with a connector housing with centerline spacing of at least .100 inch.

#### 1.2. Qualification

When tests are performed on the subject product line, procedures specified in Figure 1 shall be used. All inspections shall be performed using the applicable inspection plan and product drawing.

#### 1.3. Qualification Test Results

The Qualification Test Report, 501-292 details the successful qualification testing.

### 2. APPLICABLE DOCUMENTS AND FORMS

The following documents and forms constitute a part of this specification to the extent specified herein. Unless otherwise indicated, the latest edition of the document applies.

#### 2.1. TE Documents

- [109-197](#) Test Specification (TE Test Specification vs EIA and IEC Test Methods)
- [114-25038](#): Application Specification
- [501-292](#): Qualification Test Report

#### 2.2. Industry Documents

- EIA-364: Electrical Connector Performance Test Standards

### 3. REQUIREMENTS

#### 3.1. Design and Construction

Product shall be of the design, construction, materials and physical dimensions specified on the applicable product drawing.

#### 3.2. Materials:

- Contact: Copper alloy, duplex plated gold and tin over nickel plating
- Housing: Polyamide, black, glass filled, UL94V-0

### 3.3. Ratings

Voltage	Current	Temperature
300 VAC	Signal Application Only	-65 to 105° C

### 3.4. Test Requirements and Procedures Summary

Unless otherwise specified, all tests shall be performed at ambient environmental conditions.

TEST DESCRIPTION	REQUIREMENT	PROCEDURE								
Initial examination of product	Meets requirements of product drawing and Application Specification 114-25038.	Visual, dimensional and functional per applicable quality inspection plan.								
<b>ELECTRICAL</b>										
Termination resistance.	15 milliohms maximum initial. 20 milliohms maximum final.	EIA 364-23. Subject mated contacts assembled in housing to 20 mv maximum open circuit at 100 ma maximum. See Figure 3.								
Insulation resistance.	5000 megohms minimum initial. 1000 megohms minimum final.	EIA 364-21. Test between adjacent contacts of samples.								
Dielectric withstanding voltage.	<table border="1" style="display: inline-table; vertical-align: top;"> <tr> <td>Test Voltage</td> <td>Altitude, Feet</td> </tr> <tr> <td>750</td> <td>Sea level</td> </tr> <tr> <td>300</td> <td>50000</td> </tr> <tr> <td>275</td> <td>70000</td> </tr> </table>	Test Voltage	Altitude, Feet	750	Sea level	300	50000	275	70000	EIA 364-20. Test between adjacent contacts of samples.
Test Voltage	Altitude, Feet									
750	Sea level									
300	50000									
275	70000									
<b>MECHANICAL</b>										
Vibration, sinusoidal	No discontinuities of 1 microsecond or longer duration. See Note.	EIA 364-28, Condition III. Subject mated samples to 15 G's between 10-2000-10 Hz traversed in 20 minutes. 4 hours in each of 3 mutually perpendicular planes. See Figure 4.								
Physical shock.	No discontinuities of 1 microsecond or longer duration. See Note.	EIA 364-27, Condition E. Subject mated samples to 50 G's sawtooth shock pulses of 11 milliseconds duration. 3 shocks in each direction applied along 3 mutually perpendicular planes, 18 total shocks. See Figure 4.								
Durability.	See Note.	EIA 364-09. Mate and unmate samples for 200 cycles for 30 µin gold plating, 75 cycles for 15 µin gold plating, and 25 cycles for tin-lead plating at maximum rate of 200 cycles per hour.								

Figure 1 (continued)

Contact retention.	Contacts shall not dislodge.	EIA 364-29, Method B. Apply axial load of 3 pounds to contacts.
Mating force.	9 ounces maximum for gold contacts. 21 ounces maximum for tin contacts.	EIA 364-13. Measure force necessary to mate samples at maximum rate of 1 inch per minute.
Unmating force.	1.5 ounces minimum.	EIA 364-13. Measure force necessary to unmate samples at maximum rate of 1 inch per minute.

**ENVIRONMENTAL**

Thermal shock.	See Note.	EIA 364-32, Method A, Condition II. Subject mated samples to 5 cycles between -65 and 105°C.
Humidity-temperature cycling.	See Note.	EIA 364-31, Method IV, No Cold Shock. Subject mated samples to 10 cycles between 25 and 65°C at 95% RH.
Temperature life.	See Note.	EIA 364-17, Method A. Subject mated samples to temperature life at 105°C for 500 hours.
Mixed flowing gas.	See Note.	EIA 364-64, Class IIIA. Subject mated samples to environmental class III for 20 days.



**NOTE**

*Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Requalification Test Sequence shown in Figure 2.*

Figure 1 (end)

3.5. Product Qualification and Requalification Test Sequence

Test or Examination	Test Group (a)				
	1	2	3 (c)	4 (d)	5 (e)
	Test Sequence (b)				
Examination of Product	1, 9	1, 5	1, 5	1, 5	1, 9
Termination Resistance	3, 7	2, 4	2, 4	2, 4	
Insulation Resistance					2, 6
Dielectric Withstanding Voltage					3, 7
Vibration	5				
Physical Shock	6				
Durability	4				
Contact Retention					
Mating Force	2				
Unmating Force	8				
Thermal Shock					4
Humidity-temperature cycling				3 (f)	5
Temperature Life		3 (f)			
Mixed flowing gas			3 (f)		



**NOTE**

- (a) See paragraph 4.1.A.
- (b) Numbers indicate sequence in which tests are performed.
- (c) Applies to gold plated product only.
- (d) Applies to tin plated product only.
- (e) Shall be unmounted.
- (f) Precondition samples with 10 cycles durability.

Figure 2

**4. QUALITY ASSURANCE PROVISIONS**

4.1. Qualification Testing

A. Sample Selection

Samples shall be prepared in accordance with applicable Instruction Sheets and shall be selected at random from current production. All test groups shall each consist of a minimum of 5 connectors containing at least 30 contacts total with receptacles crimped to wire and an equal amount of posts of identical plating type and thickness to mate with receptacles. Test group 1 shall consist of minimum and maximum position size connectors available. All contacts shall be crimped to appropriate size tin plated stranded copper test conductors in accordance with Application Specification 114-25038.

## B. Test Sequence

Qualification inspection shall be verified by testing samples as specified in Figure 2.

### 4.2. Requalification Testing

If changes significantly affecting form, fit or function are made to product or manufacturing process, product assurance shall coordinate requalification testing, consisting of all or part of original testing sequence as determined by development/product, quality and reliability engineering.

### 4.3. Acceptance

Acceptance is based on verification that product meets requirements of Figure 1. Failures attributed to equipment, test setup or operator deficiencies shall not disqualify product. When product failure occurs, corrective action shall be taken and samples resubmitted for qualification. Testing to confirm corrective action is required before resubmittal.

### 4.4. Quality Conformance Inspection

The applicable quality inspection plan will specify sampling acceptable quality level to be used. Dimensional and functional requirements shall be in accordance with applicable product drawing and this specification.

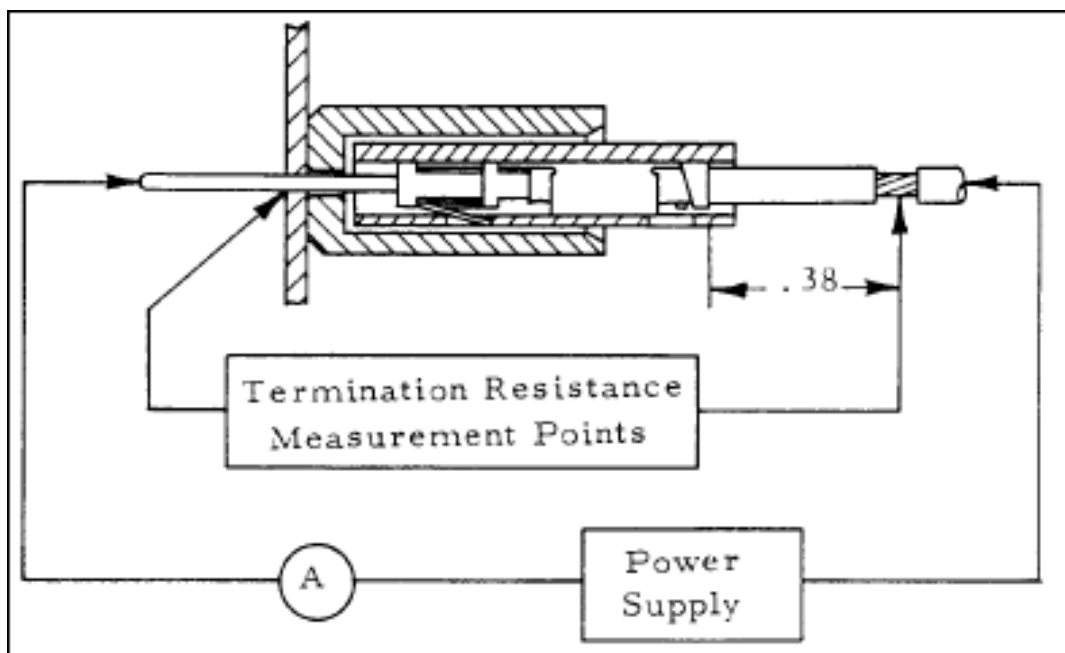


Figure 3  
Termination Resistance Measurement Points

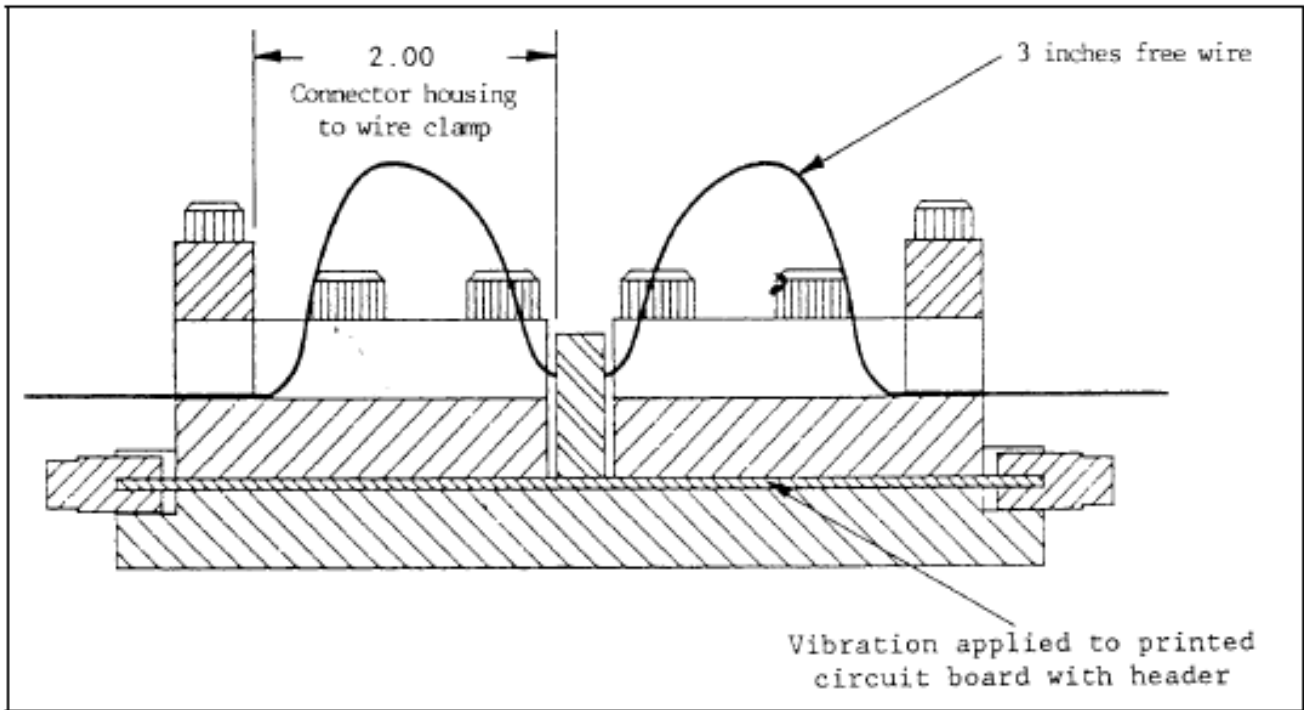


Figure 4  
Vibration & Physical Shock Mounting Fixture